


<b>Search Notes</b>  	<b>Application/Control No.</b>  10065159	<b>Applicant(s)/Patent Under Reexamination</b>  TKACZYK ET AL.
	<b>Examiner</b>  Nguyen, Tran N	<b>Art Unit</b>  3626

SEARCHED			
Class	Subclass	Date	Examiner
705	2-3 (cursory with keyword)	05/30/2007	Nguyen, Tran N
705	2-3	9/23/2010	/TN/

SEARCH NOTES		
Search Notes	Date	Examiner
705/7 (consulted B. Van Doren A.U. 3623)	03/07/2007	Nguyen, Tran N
US patent database (EAST)	05/30/2007	Nguyen, Tran N
Reviewed IFW record of 09/655,667	05/30/2007	Nguyen, Tran N
Please see attachment for Examiner's search strategy.		
US patents (EAST)	11/14/2007	/TN/
NPL (Google/Google Scholar)	11/14/2007	/TN/
Full Dialog search template (EIC 3600)	9/23/2010	/TN/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
705	2	9/23/2010	/TN/

/Tran Nguyen/  
Examiner.Art Unit 3626